UTT200N02 Preliminary Power MOSFET

200 A, 20 V N-CHANNEL POWER MOSFET

DESCRIPTION

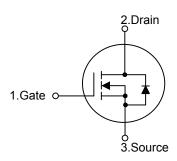
The UTC **UTT200N02** is an N-channel power MOSFET using UTC's advanced technology to provide customers with a minimum on-state resistance and superior switching performance.

The UTC **UTT200N02** is generally applied in synchronous Rectification or DC to DC convertor.



- * $V_{DS} = 20V$
- * I_D= 200A
- * $R_{DS(ON)}$ =2.0m Ω (Typ.) @ V_{GS} =10V
- * Low Gate Charge (Typical 84nC)
- * High Switching Speed
- * High Power and Current Handling Capability
- * RoHS Compliant

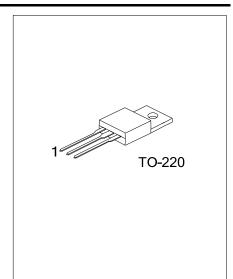
■ SYMBOL



■ ORDERING INFORMATION

Ordering Number		Dookogo	Pin Assignment			Dooking	
Lead Free	Halogen Free	Package	1	2	3	Packing	
UTT200N02L-TA3-T		TO-220	G	D	S	Tube	
Note: Pin Assignment: G: Gate D: Drain S: Source							

UTT200N02L-TA3-T
(1)Packing Type
(1) T: Tube
(2)Package Type
(2) TA3: TO-220
(3) Lead Free
(3) G: Halogen Free, L: Lead Free



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■ **ABSOLUTE MAXIMUM RATINGS** (T_C=25°C, unless otherwise specified)

PARAMETER		SYMBOL	RATINGS	UNIT
Drain-Source Voltage		V_{DSS}	20	V
Gate-Source Voltage		V_{GSS}	±20	V
Drain Current	Continuous (Silicon Limited)	I _D	200 (Note 2)	Α
Drain Current	Pulsed (Note 3)	I_{DM}	800	Α
Single Pulsed Avalanche Energy (Note 4)		E _{AS}	864	mJ
Peak Diode Recovery dv/dt (Note 5)		dv/dt	6.0	V/ns
Power Dissipation		D	214	W
Derate above 25°C		P_{D}	1.43	W/°C
Junction Temperature		T_J	+150	°C
Storage Temperature Range		T _{STG}	-55~+175	°C

Note: 1. Absolute maximum ratings are those values beyond which the device could be permanently damaged. Absolute maximum ratings are stress ratings only and functional device operation is not implied.

- 2. Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 100A.
- 3. Repetitive Rating: Pulse width limited by maximum junction temperature
- 4. L = 3mH, I_{AS} =24A, V_{DD} = 20V, R_{G} = 25 Ω , Starting T_{J} = 25 $^{\circ}$ C
- 5. $I_{SD} \le 200A$, di/dt $\le 200A/\mu s$, $V_{DD} \le BV_{DSS}$, Starting $T_J = 25^{\circ}C$

■ THERMAL DATA

PARAMETER	SYMBOL	RATINGS	UNIT
Junction to Ambient	θ_{JA}	62.5	°C/W
Junction to Case	θ_{JC}	0.7	°C/W



■ ELECTRICAL CHARACTERISTICS (T_C=25°C, unless otherwise specified)

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNIT	
OFF CHARACTERISTICS							
Drain-Source Breakdown Voltage	BV _{DSS}	I _D =250μA, V _{GS} =0V	20			V	
Breakdown Voltage Temperature Coefficient	△BV _{DSS} /△T _J	Reference to 25°C, I _D =250μA		30		mV/°C	
Drain-Source Leakage Current	I _{DSS}	V _{DS} =20V, V _{GS} =0V			10	μΑ	
Gate- Source Leakage Current Forward Reverse	- I _{GSS}	V_{GS} =+20V, V_{DS} =0V V_{GS} =-20V, V_{DS} =0V			+100	nA nA	
ON CHARACTERISTICS							
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{DS}=V_{GS}$, $I_{D}=250\mu A$	1.0		3.0	V	
Static Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =80A		2.0	2.4	mΩ	
DYNAMIC PARAMETERS							
Input Capacitance	C _{ISS}			5490	7300	pF	
Output Capacitance	Coss	V_{GS} =0V, V_{DS} =25V, f=1.0MHz		1220	1620	pF	
Reverse Transfer Capacitance	C _{RSS}	1 Γ		155	233	pF	
SWITCHING PARAMETERS							
Total Gate Charge at 10V	$Q_{G(tot)}$			84	109	nC	
Gate to Source Charge	Q_GS	V_{GS} =10V, V_{DS} =16V, I_{D} =80A		19		nC	
Gate Charge Threshold to Plateau	Q_{GS2}	(Note 1, 2)		9.5		nC	
Gate to Drain Charge	Q_GD			12		nC	
Turn-ON Delay Time	t _{D(ON)}			17	44	ns	
Rise Time	t _R	V_{DD} =10V, I_{D} =80A, R_{GEN} =4.7 Ω ,		8	26	ns	
Turn-OFF Delay Time	t _{D(OFF)}	V _{GS} =10V (Note 1, 2)		71	152	ns	
Fall-Time	t _F			17	44	ns	
SOURCE- DRAIN DIODE RATINGS AND CHARACTERISTICS							
Maximum Body-Diode Continuous	la				200	Α	
Current	I _S				200	Α	
Maximum Body-Diode Pulsed Current	I _{SM}				800	Α	
Drain-Source Diode Forward Voltage	V_{SD}	I _{SD} =200A, V _{GS} =0V			1.3	V	

Notes: 1. Pulse Test: Pulse width ≤ 300µs, Duty cycle ≤ 2%

2. Essentially independent of operating temperature Typical Characteristics



■ TEST CIRCUITS AND WAVEFORMS

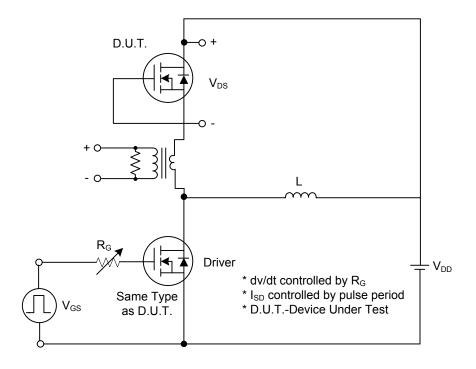


Fig. 1A Peak Diode Recovery dv/dt Test Circuit

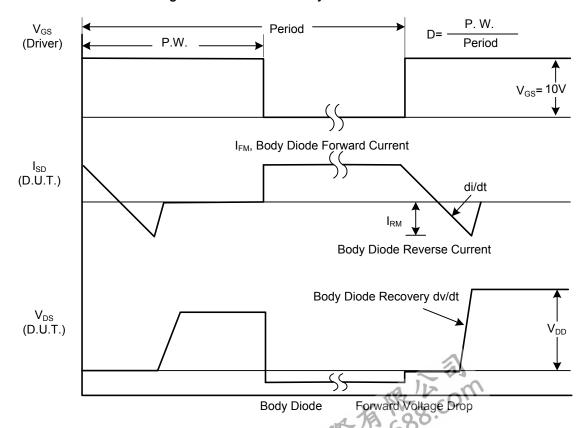
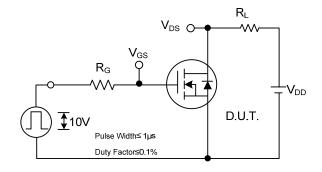


Fig. 1B Peak Diode Recovery dv/dt Waveforms

TEST CIRCUITS AND WAVEFORMS (Cont.)



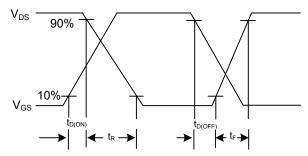
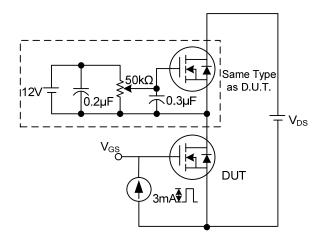


Fig. 2A Switching Test Circuit

Fig. 2B Switching Waveforms



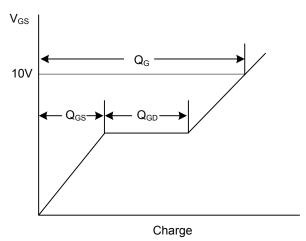
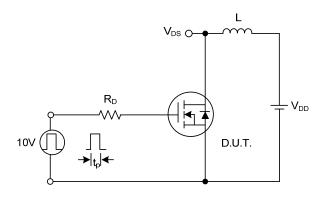


Fig. 3A Gate Charge Test Circuit

Fig. 3B Gate Charge Waveform



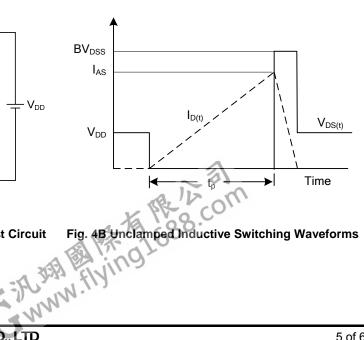


Fig. 4A Unclamped Inductive Switching Test Circuit

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